

Study of Complex Multi-Bandpass DWA algorithm for I-Q Signal Generation

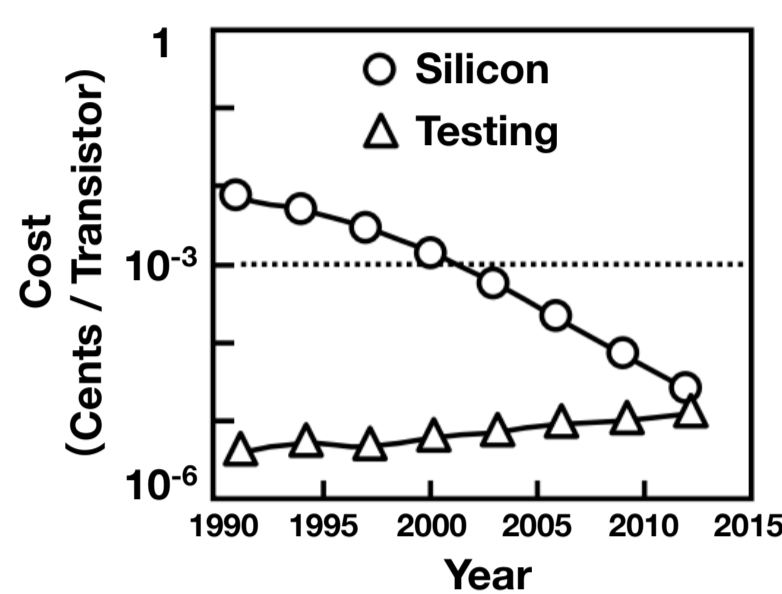
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Introduction

Research Background

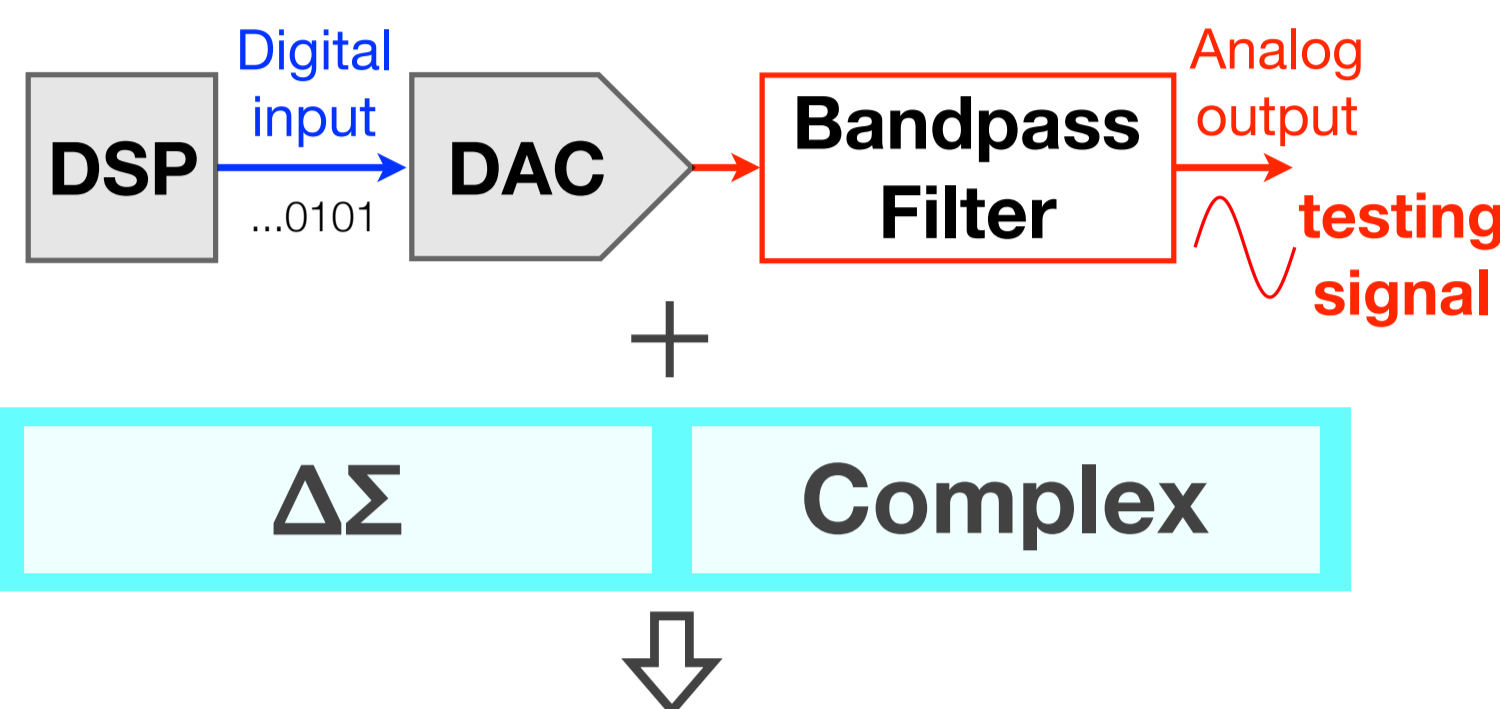
Demand for communication IC testing



Silicon cost : Lower
 Testing cost : Higher

Research Objective

High quality testing



Low cost, high quality signal

Research Objective

Multi-bit DA modulator (2~3bit)

Linearity degradation

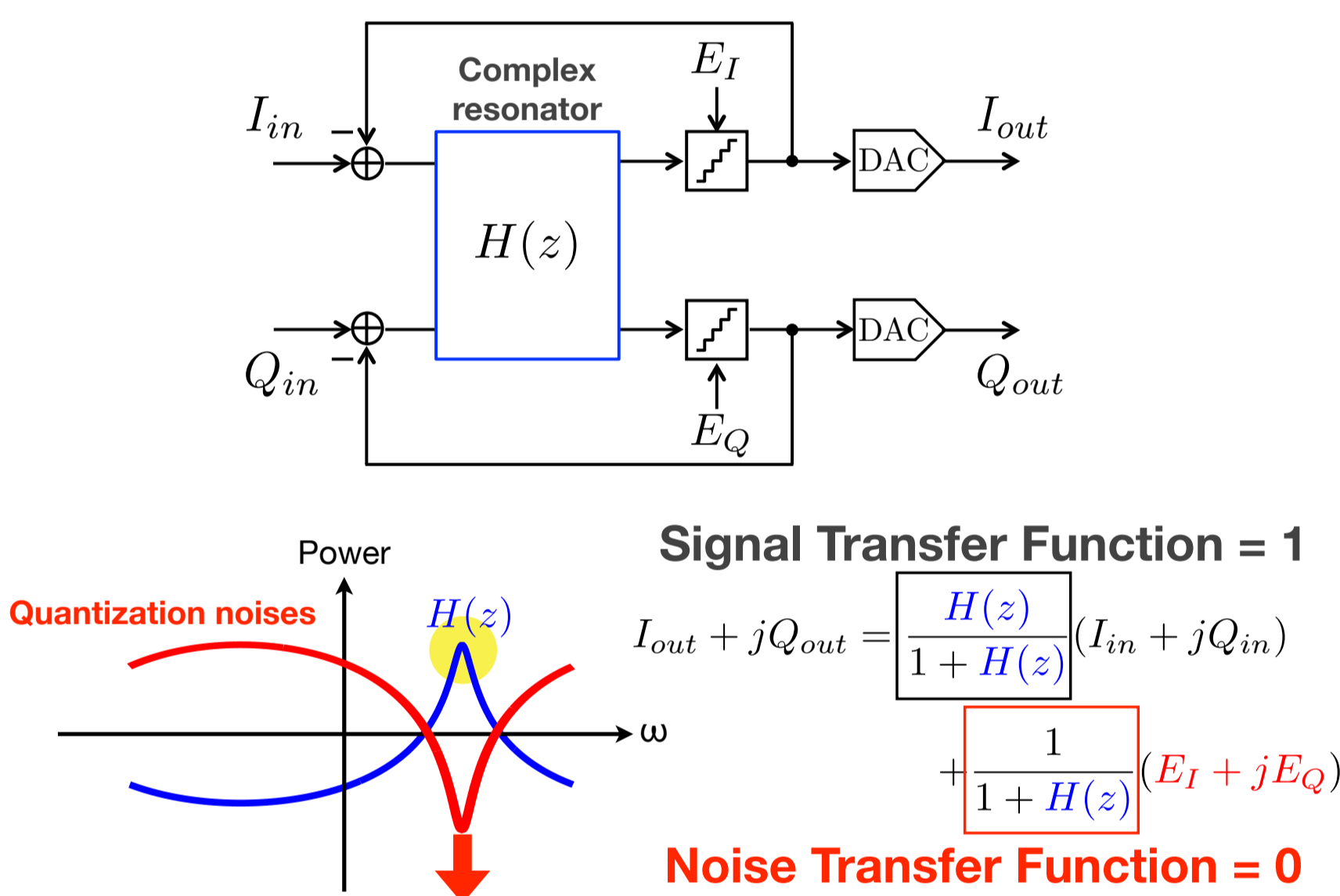
Low quality signal

DWA algorithm

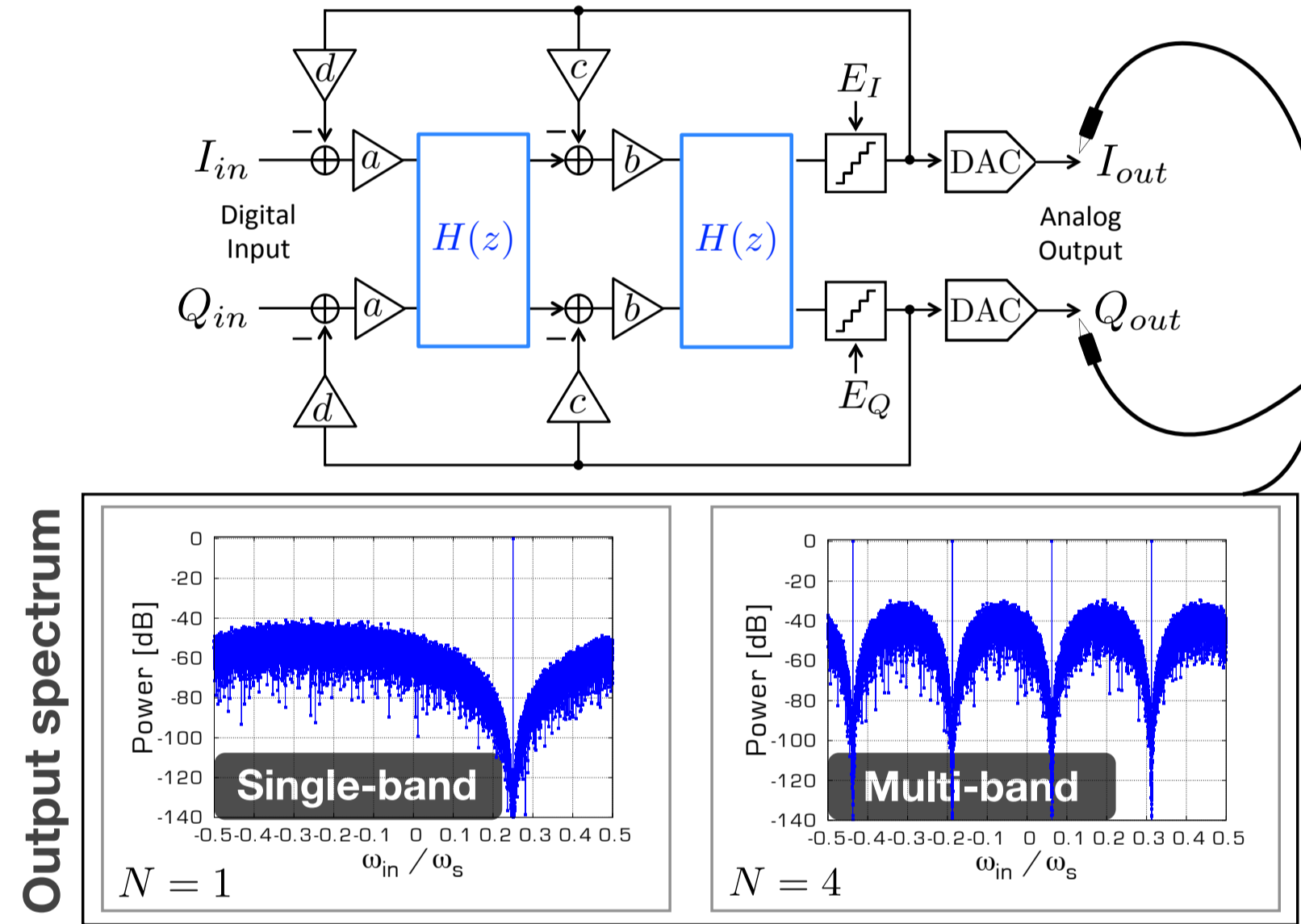
High quality signal

Complex ΔΣ DA modulator

Principle of complex BP noise shape

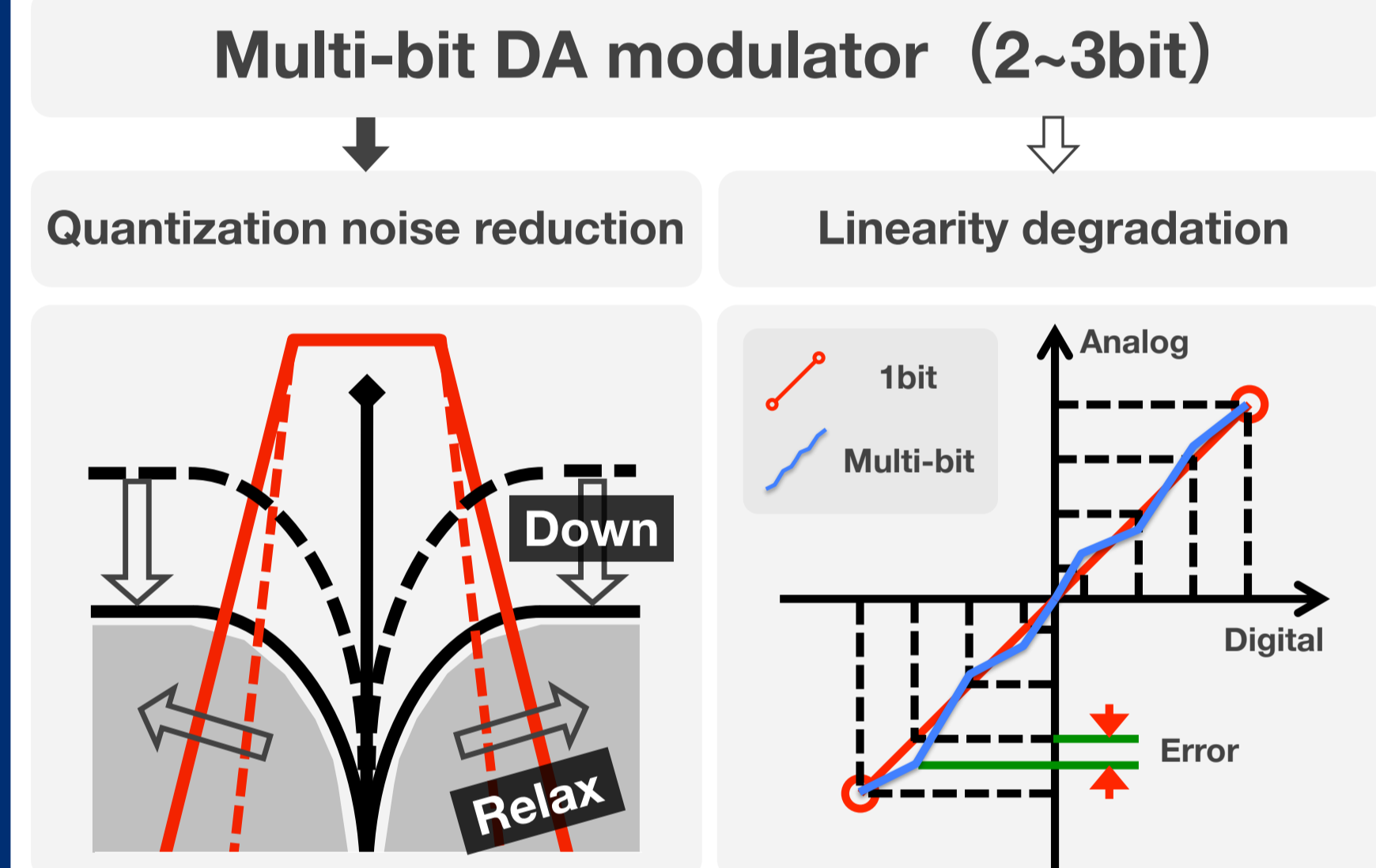


2nd-order complex multi-BP ΔΣ DAC



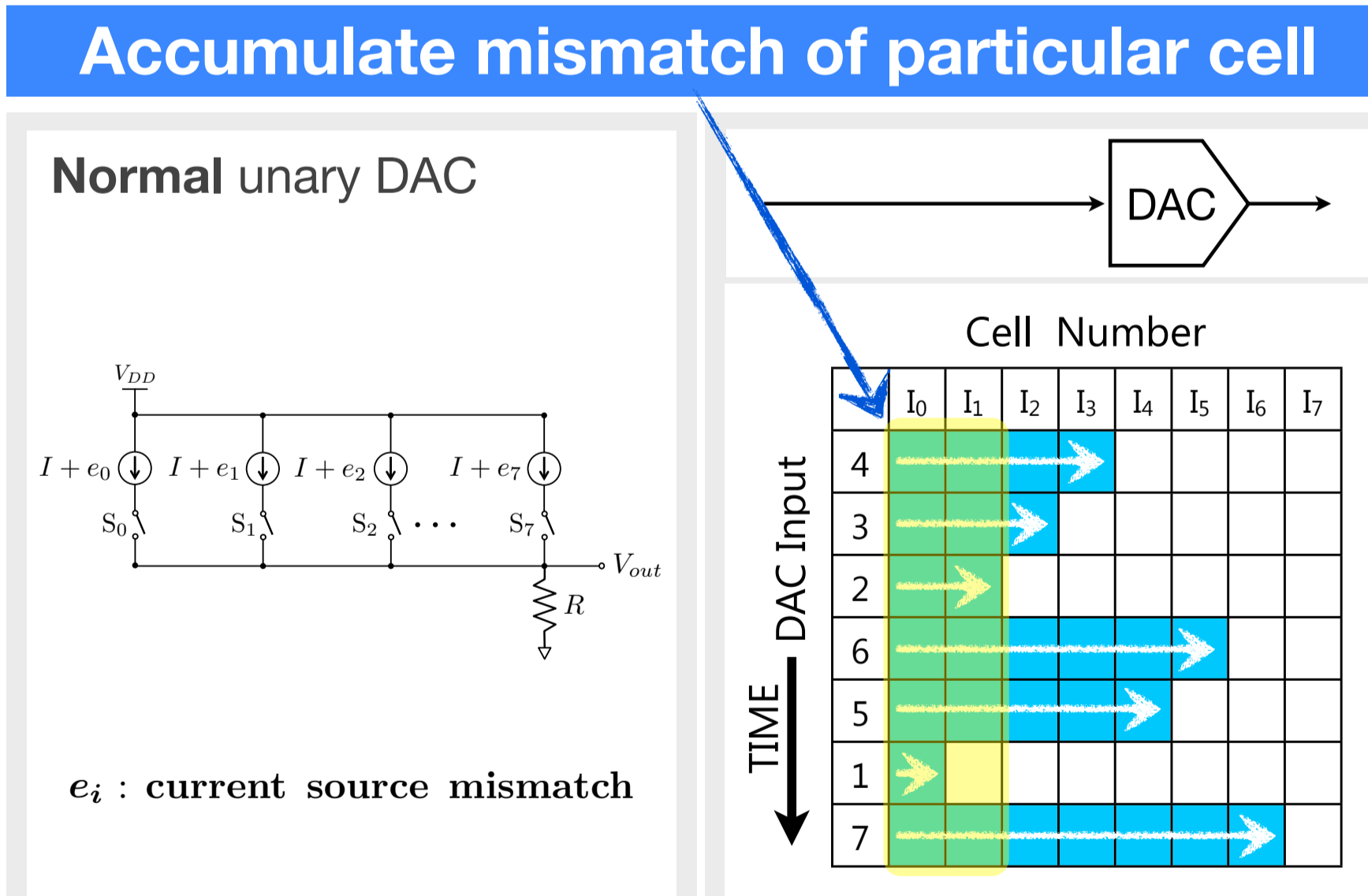
DWA algorithm

Multi-bit DA modulator

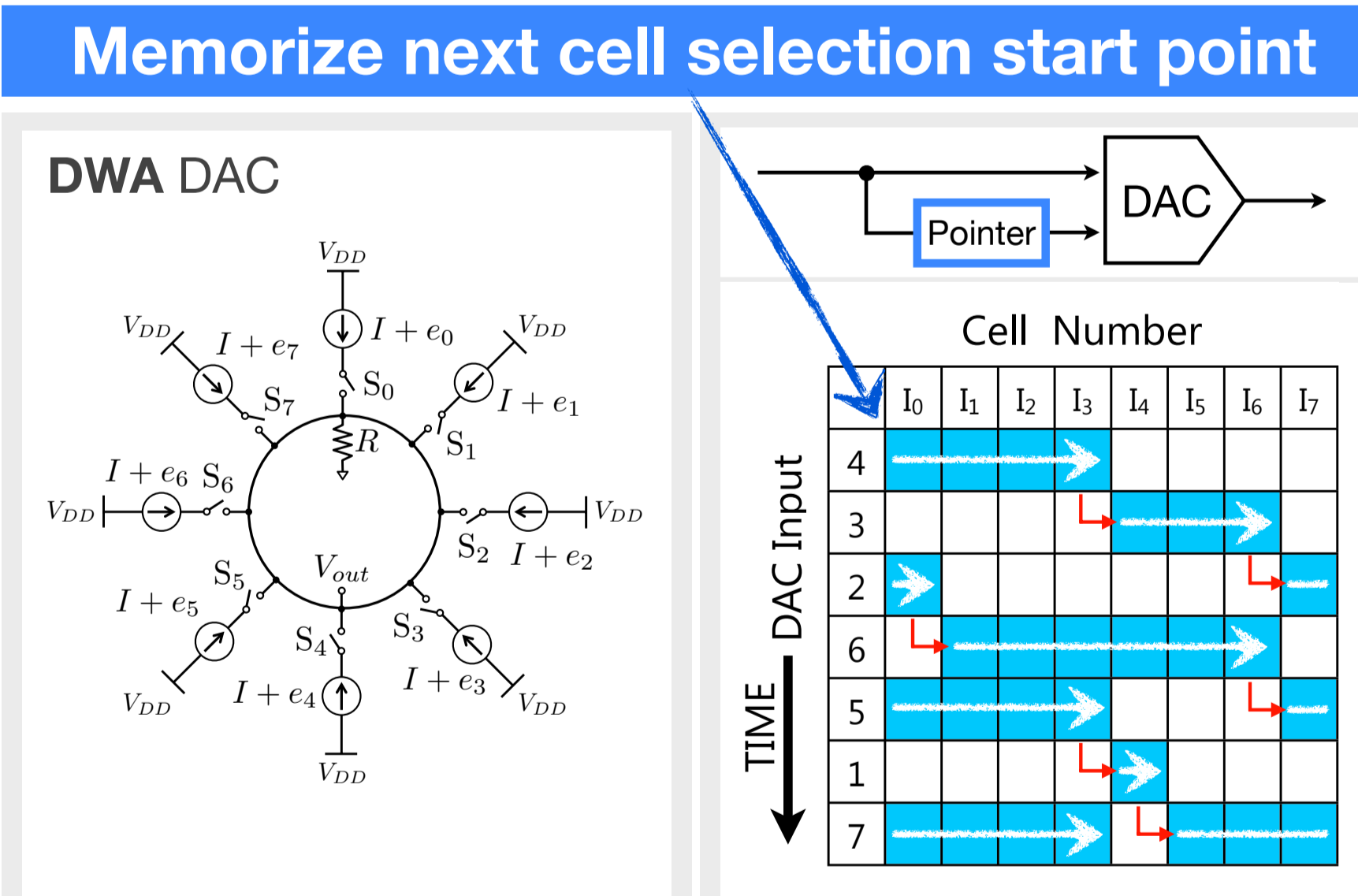


*Data Weighted Averaging | Select the element with DSP algorithm

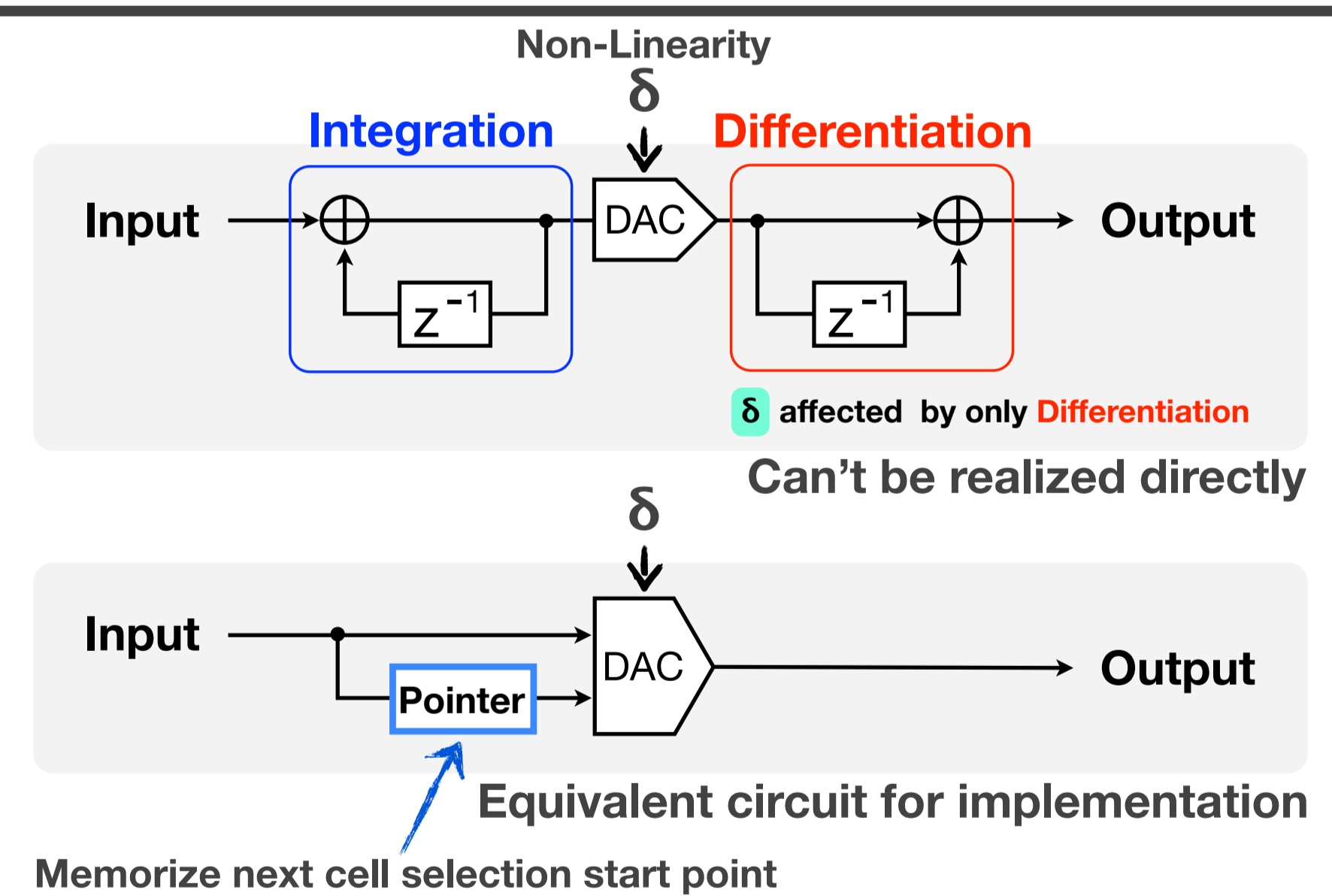
Multi-bit DAC



Multi-bit DAC + DWA*

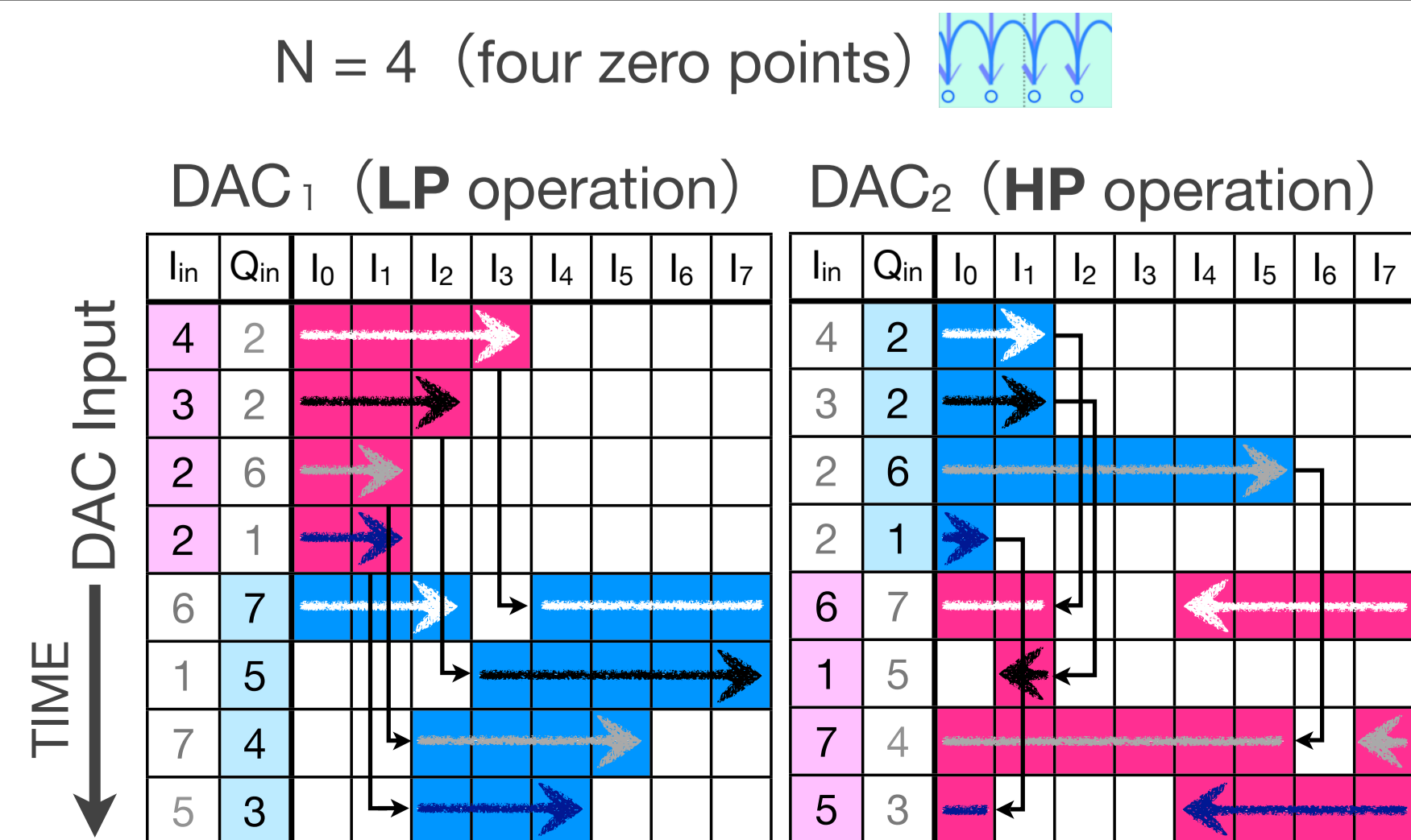


DWA = ΔΣ

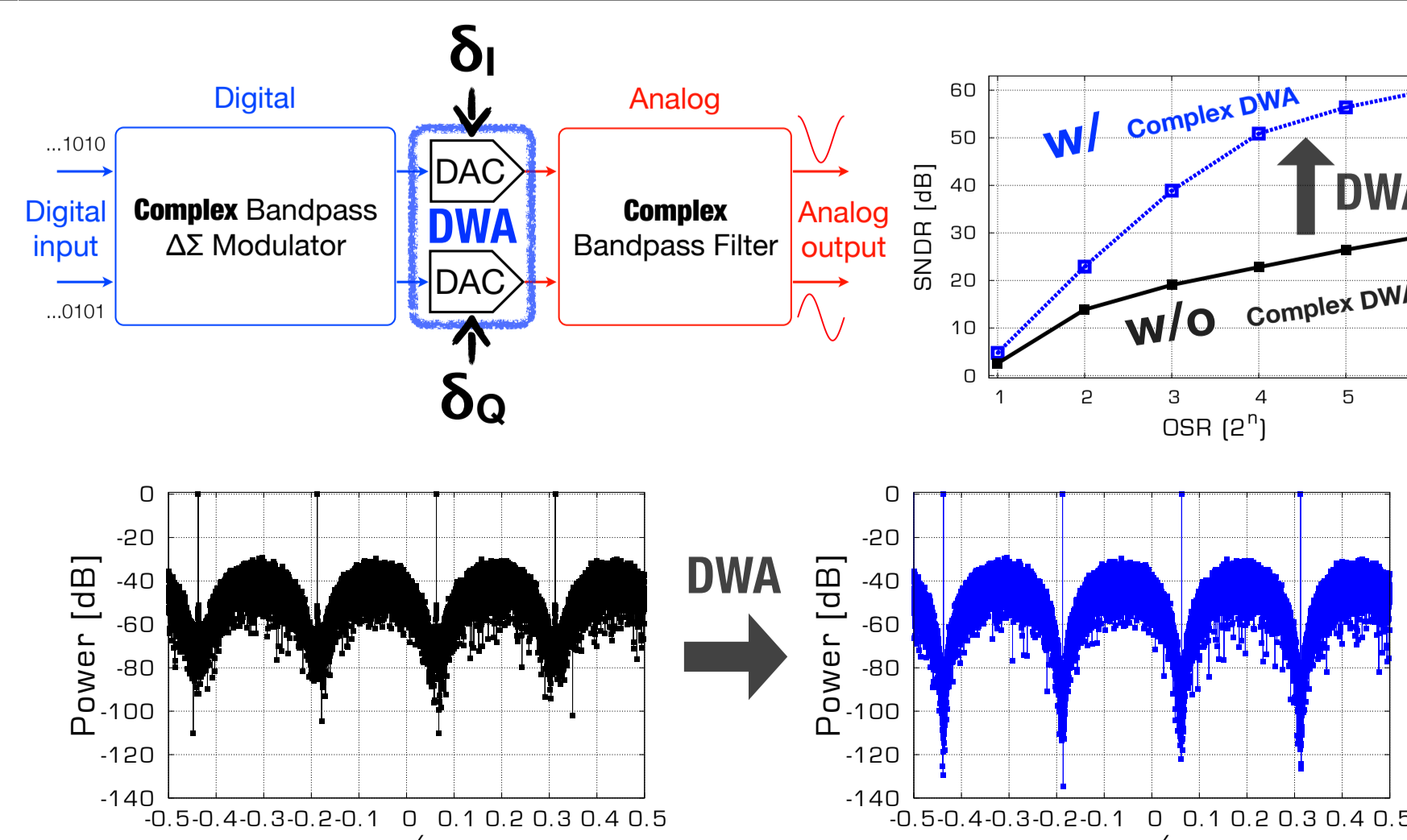


Complex multi-bandpass DWA

Complex Multi-Bandpass DWA algorithm



Simulation result ~Actual Non-Linear DAC + DWA~



Summary

- ▶ I,Q signal generation with digital centric for testing communication IC.
 - ▶ Complex multi-BP ΔΣ DAC
 - ▶ Multi-bit DAC
 - Relaxes the analog filter requirements
 - ✗ Degrades system linearity
 - ○ DWA algorithm
- Low cost, high quality I,Q signal generation.